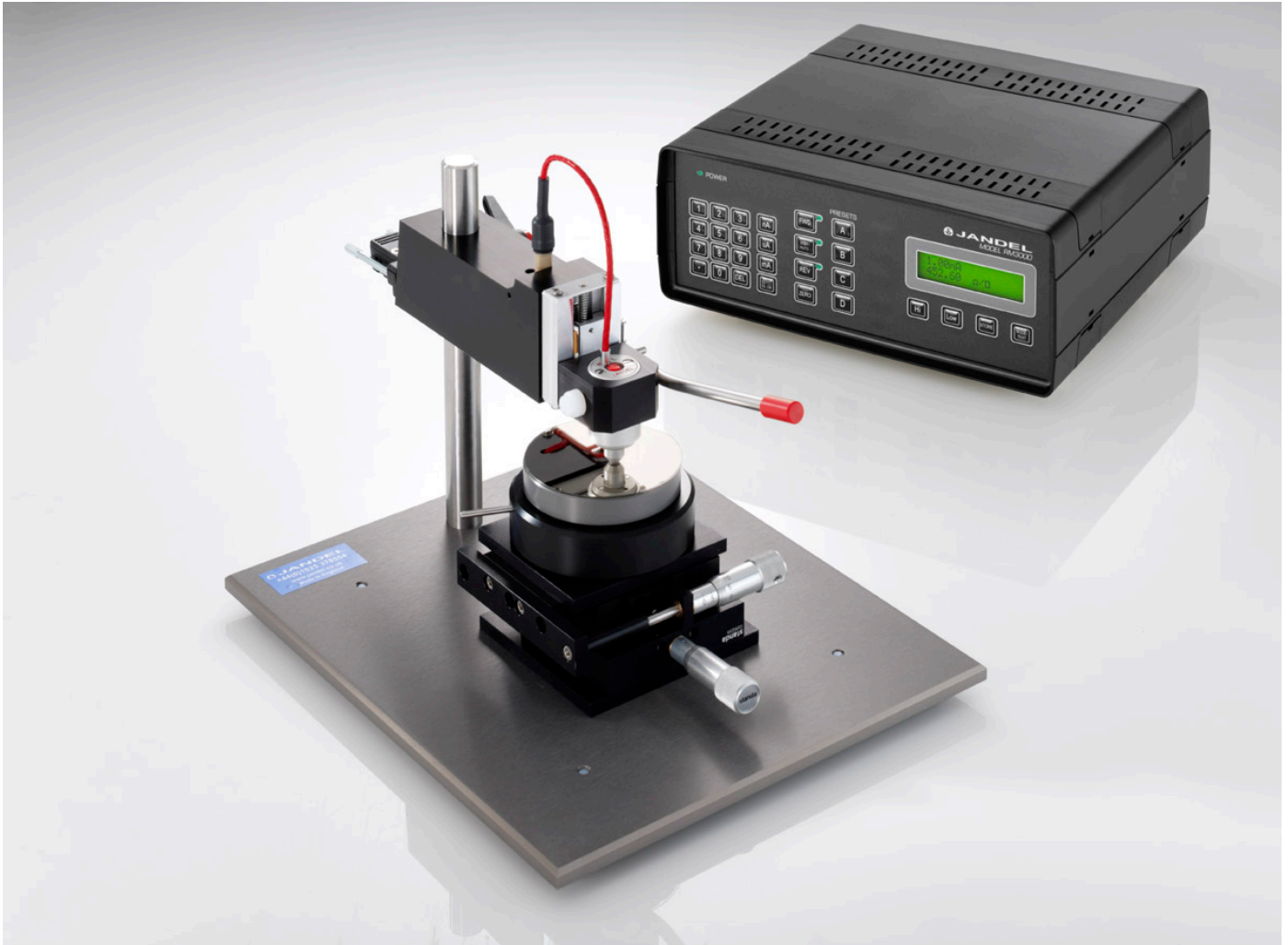


Jandel Engineering Limited



Jandel Multipurpose Measurement System

Jandel Engineering Limited offers the RM3000 Test Unit in combination with the Multiheight Probe stand with micrometer controlled X-Y stage as a solution for measurements on sample sizes from several mm square up to 300mm. The system can be used for measuring samples such as very small sized thin layers, 300mm wafers, or ingots up to 250mm high (thicker samples can be accommodated on request).

<i>Max. sample size</i>	Samples up to 250mm diameter (300mm option at no extra cost)
<i>Max. sample thickness</i>	Samples up to 250mm high can be measured (higher on request)
<i>Microswitch</i>	Prevents current flow when probe is not in contact with the sample
<i>Manual Control</i>	Simple lever operation for probe contact and removal
<i>Simple set up</i>	Single wire connects the probe stand and RM3000
<i>X-Y Stage</i>	Offers micrometer controlled manipulation of small samples

System Configuration

Component parts:

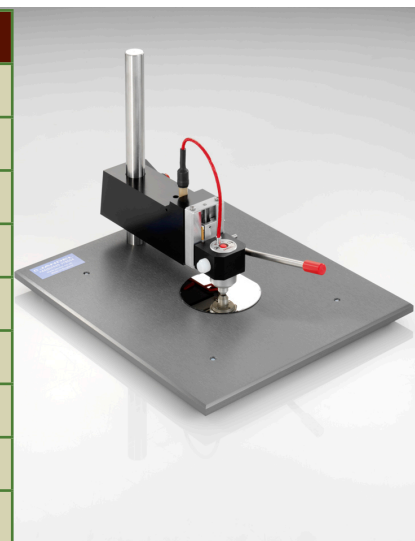
- A. Measurement Base - 1pc
- B. Multiheight assembly - 1pc
- C. Multiheight Column - 1pc
- D. Four point probe head - 1pc
- E. Connecting cable - 1pc
- F. Micrometer table - 1pc

System Footprint

- A. Multiheight Base: 250mm W x 290mm L x 8mm H (320mm x 370mm x 8mm option)
- B. Multiheight Probe assembly: 60mm W x 280mm L x 80mm H (60mm x 330mm x 80mm option)
- C. Multiheight Column: 19mm diameter, 200mm L (up to 1m on request)

Type	Tip R	Force	Spacing
A	40u	100g	1mm
B	100u	100g	1mm
C	200u	100g	1mm
D	500u	70g	1mm
E	40u	200g	1.591mm
F	40u	100g	0.635mm
G	100u	100g	0.635mm
H	200u	100g	0.635mm

Type A-D and F-H are user adjustable in the range 60g-150g and supplied at value shown



If you require any further information on the Jandel Multipurpose measurement system please contact us using the details below

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